

Factory Witness

Characterization

LID, LS or CID

CID

Characterization

Thermal Cycling	Damp Heat	Mechanical Stress Sequence	Potential Induced Degradation	UVID Sensitivity	PAN File & IAM Profile	LETID Sensitivity	Hail Test-To-Failure	SML Test-To-Failure	Backsheet Durability Sequence	Field Exposure
TC 200	DH 1000	SML (tracker or corner-mount)	85°C, 85%RH MSV (+ and -) 192 hrs	UV 120 kWh/m ² 60°C front	PAN File	LETID 162 hrs 75°C, 2*(Isc-Imp)	Hail (up to three hail sizes)	SML (tracker or corner-mount)	DH 200	Field Exposure 6 Months
Characterization	Characterization			Characterization	IAM Profile	Characterization			UV 65 kWh/m ² 80°C rear	
TC 200	DH 1000	DML1000	Characterization	LS stabilization (≥1kWh/m ²)*		LETID 162 hrs 75°C, 2*(Isc-Imp)			Characterization	Characterization
Characterization	Characterization	Characterization	UV stabilization* (0.2 kWh/m ²)	Characterization		Characterization			TC 50 + HF 10	Field Exposure 6 Months
TC 200	LS stabilization (≥1kWh/m ²)*	TC 50 + HF 10	Characterization	UV 120 kWh/m ² 60°C front					UV 65 kWh/m ²	Characterization
Characterization	Characterization	Characterization		Characterization					Characterization	LS stabilization (≥1kWh/m ²)*
				UV 120 kWh/m ² 60°C front					TC 50 + HF 10	Characterization
				Characterization					UV 65 kWh/m ²	
				LS stabilization (≥1kWh/m ²)*					Characterization	TC 50 + HF 10
				Characterization					TC 50 + HF 10	UV 6.5 kWh/m ²
				Optional					Characterization	

Test Abbreviations

CID: Current induced degradation
 DH: Damp heat
 DML: Dynamic mechanical load
 HF: Humidity freeze
 IAM: Incidence angle modifier
 LETID: Light and elevated temperature induced degradation
 LID: Light induced degradation
 *optional stabilization, based on test results

LS: Light soaking
 MSV: Maximum system voltage
 PAN File: PVSyst .pan file
 SML: Static mechanical load
 TC: Thermal cycling
 UV: Ultraviolet
 UVID: Ultraviolet induced degradation

Characterizations

IV: Flash test at STC
 EL: EL image at Isc
 VI: Visual inspection
 WL: Wet leakage
 LIC: Flash test at 200W/m²

LCEL: EL image at 1/10*Isc
 Diode: Diode test
 Color: Backsheet color measurement
 Edge: Edge pinch measurement

Not all measurements are taken at each step